

FORM PTO-1449

U.S. Department of Commerce
Patent and Trademark OfficeAtty. Docket
P29771Application No.
10/576,023INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

(Use several sheets if necessary)

Applicant
Kimiaki TOSHIKIYOI.A. Filing Date
April 17, 2006Group
Not Yet Assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2006/	0 1 0 2 8 2 7	05/18/06	KASUGA et al.			
		5 7 4 2 4 3 3	04/21/98	SHIONO et al.			
		5 5 6 1 5 5 8	10/01/96	SHIONO et al.			
	2003/	0 1 6 8 6 7 9	09/11/03	NAKAI et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
	2001	- 1 9 6 5 6 8	07/19/01	JAPAN				
	2000	- 0 3 9 5 0 3	02/08/00	JAPAN				
	5	- 2 5 1 6 7 3	09/28/93	JAPAN				
	2001	- 1 0 8 8 1 2	04/20/01	JAPAN			X	
	2001	- 3 1 8 2 1 7	11/16/01	JAPAN			X	
	7	- 1 1 3 9 0 7	05/02/95	JAPAN				
		0 6 4 9 0 3 7	04/19/95	E.P.O.				
	2003	- 2 2 9 5 5 3	08/15/03	JAPAN				
	2002	- 1 3 5 7 9 6	05/10/02	JAPAN			X	
	4	- 3 4 3 4 7 1	11/30/92	JAPAN			X	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

1	English Language Abstract JP 2001-196568.	07/19/01
2	English Language Abstract JP 2000-039503.	02/08/00
3	English Language Abstract JP 5-251673.	09/28/93
4	D. W. PRATHER, "Design and application of subwavelength diffractive lenses for integration with infrared photodetectors," Opt. Eng. 38(5), pages 870-878 (May 1999; Society of Photo-Optical Instrumentation Engineers).	
5	U.S. Patent Application No. 10/576,273.	filed: 4/18/06, pub: 7/19/07
6	English Language Abstract of JP 2001-108812.	04/20/01
7	English Language Abstract of JP 2001-318217.	11/16/01
8	English Language Abstract of JP 2002-135796.	05/10/02
9	English Language Abstract of JP 4-343471.	11/30/92

EXAMINER /Dwight Alex C Tejano/

DATE CONSIDERED 03/07/2011

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